

**ROCHESTER INSTITUTE OF TECHNOLOGY
MICROELECTRONIC ENGINEERING**

Wafer Thinning

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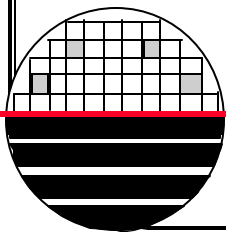
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INTRODUCTION

Wafers are often thinned before packaging. A thinner wafer allows for better heat removal, lower electrical resistance through the substrate and thinner packages. In MEMS wafer thinning allows for easier formation of thru wafer holes when combined with CMP double sided processing. We have been thinning our MEMS wafers from $\sim 500\mu\text{m}$ down to $\sim 300\mu\text{m}$ and then polishing to make thin double sided starting wafers.

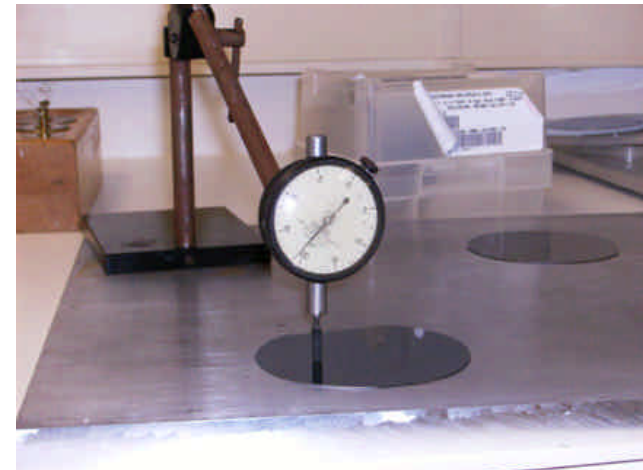


ELECTROMET GRINDING TOOL



Grinder

Platen Speed = 200 rpm
Pressure = 10 psi
Removal Rate = ~6 min/100 μ m
Time = 12 min
Water On
Power in Auto



Wafer Thickness
Measurement

GRINDING DISK



1KUY3

PSA Disc, Dia 8 In, 800 Grit, Diamond Abrasive, For Use With Orbital Sanders or Vertical Shaft Grinders with PSA Back-Up Pads, For Grinding Glass

NORTON
66260306386

1

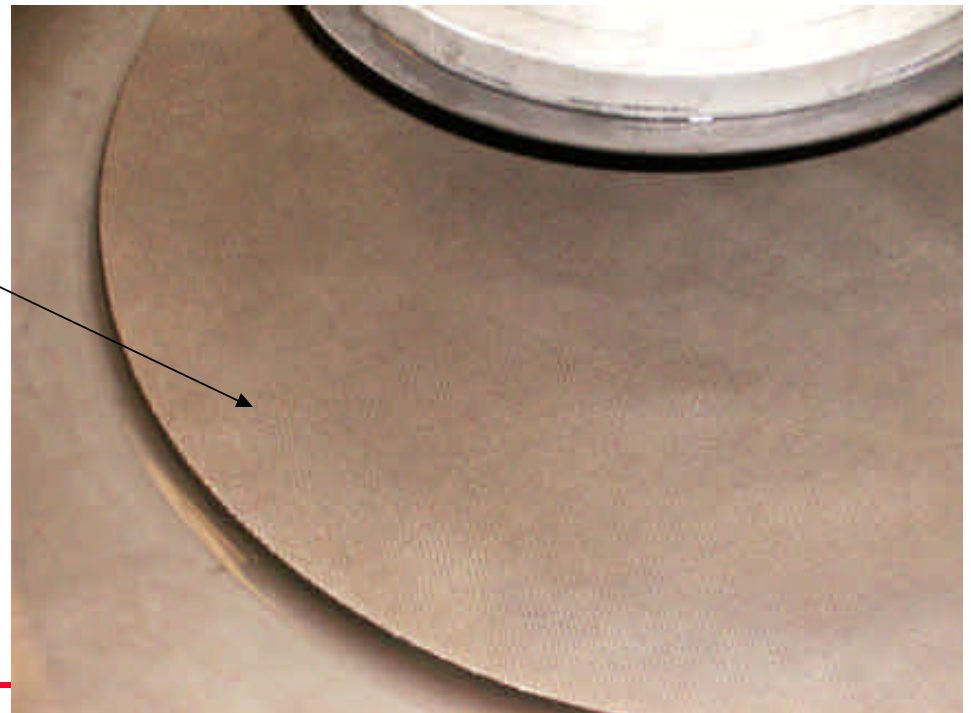
Today

\$93.50

2661

<http://www.grainger.com/Grainger/wwg/productIndex.shtml>

Grinding Disk

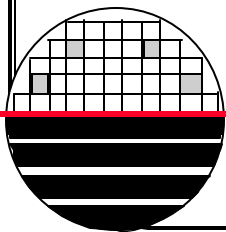


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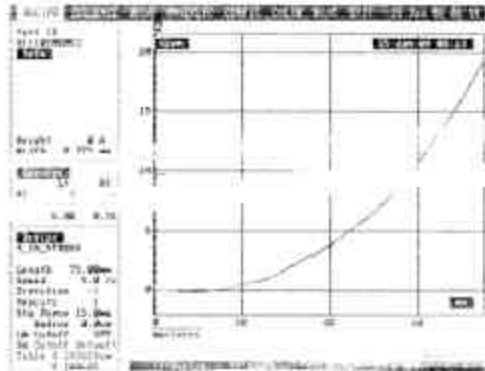
MEASUREMENT

Right now we don't have a good way to measure the wafer thickness. Just the mechanical dial micrometer shown. But that shows less than 1 mil (25 μ m) change across wafer diameter.

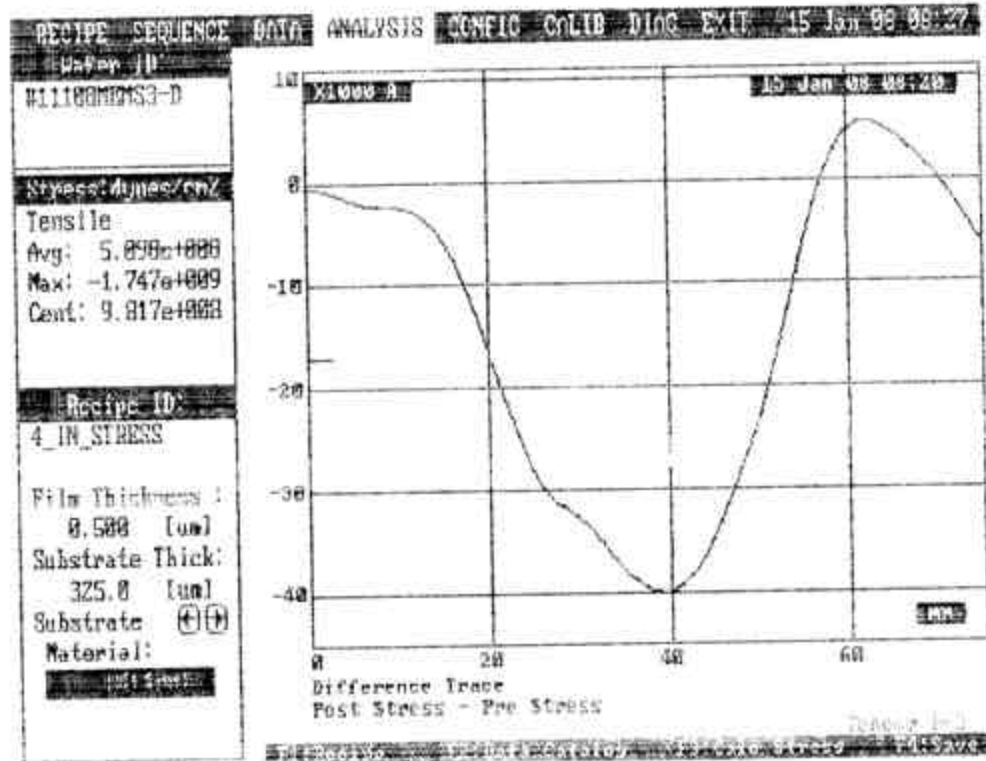
We used our long scan Tencore P2 profiler to see if that will give us a better idea of the uniformity of these processes.



MEASUREMENT RESULTS



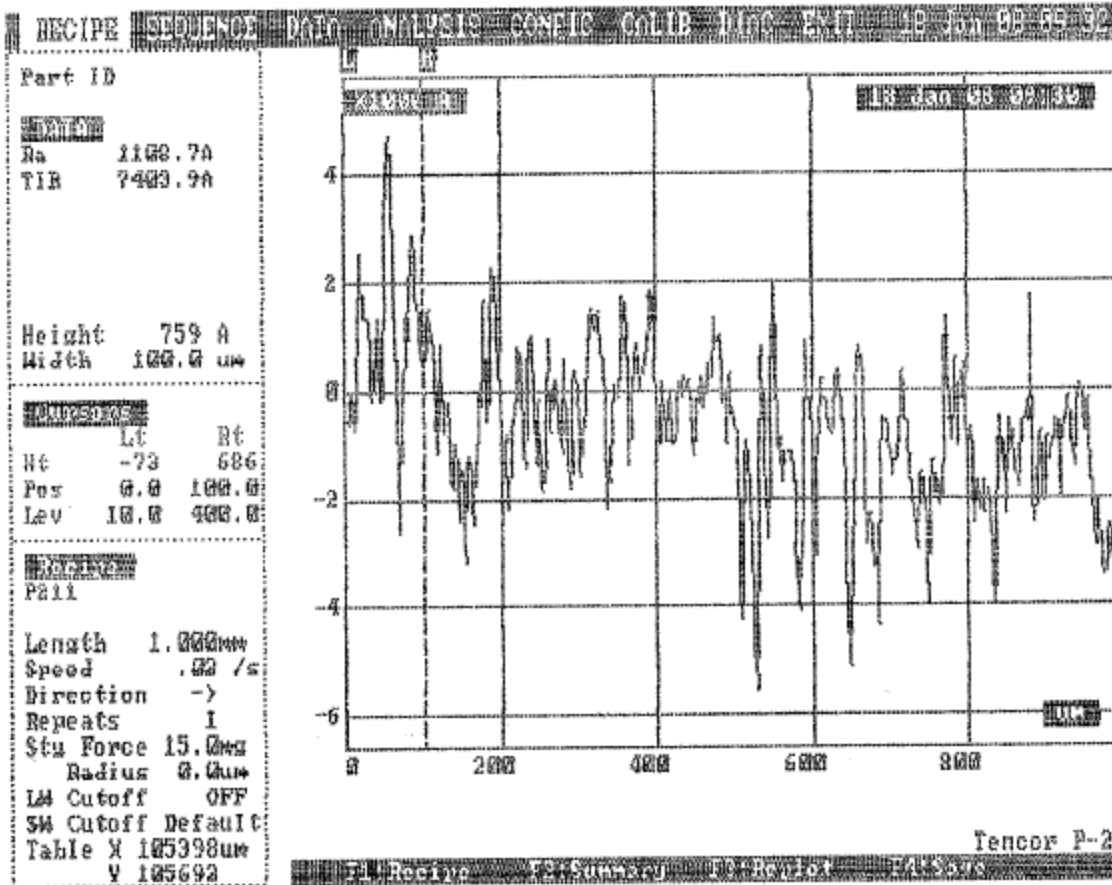
Pre Grind



Difference = Post Grind-Pre Grind

This shows center of the wafer is $\sim 4\mu\text{m}$ thinner than the edges after grind and polish.

SURFACE ROUGHNESS AFTER GRIND



Surface roughness
~1 μ m (10,000 \AA)
after grinding

After polish ~50 \AA

CMP TO OBTAIN OPTICALLY SMOOTH SURFACE

Strassbaugh CMP Tool

Slurry: Klebosol 1501-50 Colloidal Silica 5 gal pail
\$255 each, Mfg AZ Electronic Materials, Clariant's Klebosol
line of silica slurries, 50nm particles, KOH, pH 10.9, 50%
solids or equivalent slurry.

15 min per wafer

Slurry drip rate: ~1 drop/second

Down Pressure = 8 psi

Quill Speed = 70 rpm

Oscillation Speed = 6 per min

Table Speed = 50 rpm (~10 Hz)



*Roch
Micr*



Strassbaugh CMP Tool